

### General Description

- Trench Power LV (P-ch) MOSFET technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- ESD protected
- RoHS and Halogen-Free Compliant

### Applications

- This device is suitable for use as a load switch or in PWM applications.

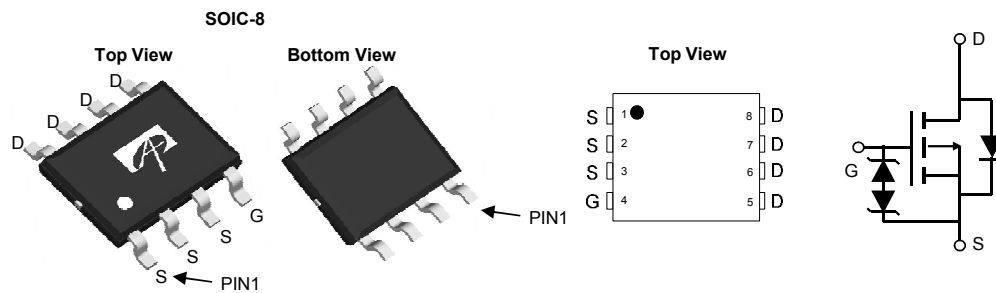
### Product Summary

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-6A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 45m $\Omega$
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 80m $\Omega$

### Typical ESD protection

100% UIS Tested  
100% Rg Tested

### HBM Class 1C



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AO4405E	SO-8	Tape & Reel	3000

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	$T_A=25^\circ\text{C}$	-6
		$T_A=70^\circ\text{C}$	-4.7
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-24	A
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$	15	A
Avalanche energy $L=0.1\text{mH}$ <sup>C</sup>	$E_{AS}, E_{AR}$	11	mJ
$V_{DS}$ Spike	$V_{SPIKE}$	-36	V
Power Dissipation <sup>B</sup>	$P_D$	$T_A=25^\circ\text{C}$	2.5
		$T_A=70^\circ\text{C}$	1.6
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	42	50	$^\circ\text{C/W}$
Maximum Junction-to-Ambient <sup>A,D</sup>		Steady-State	70	85
Maximum Junction-to-Lead	$R_{\theta JL}$	20	30	$^\circ\text{C/W}$

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
<b>STATIC PARAMETERS</b>							
B <sub>V</sub> DSS	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	-30			V	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-1 -5	μA	
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±10	μA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-2.5	-2	-1.5	V	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6A T <sub>J</sub> =125°C		29 40	45 65	mΩ	
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A		50	80	mΩ	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-6A		14		S	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A, V <sub>GS</sub> =0V		-0.76	-1	V	
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-3	A	
<b>DYNAMIC PARAMETERS</b>							
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V, f=1MHz		495		pF	
C <sub>oss</sub>	Output Capacitance				100		pF
C <sub>riss</sub>	Reverse Transfer Capacitance				56		pF
R <sub>g</sub>	Gate resistance	f=1MHz	3.5	7.5	11.5	Ω	
<b>SWITCHING PARAMETERS</b>							
Q <sub>g(10V)</sub>	Total Gate Charge	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-6A		8.8	16	nC	
Q <sub>g(4.5V)</sub>	Total Gate Charge			4.2	8	nC	
Q <sub>gs</sub>	Gate Source Charge			1.8		nC	
Q <sub>gd</sub>	Gate Drain Charge			2.0		nC	
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, R <sub>L</sub> =2.5Ω, R <sub>GEN</sub> =3Ω		9		ns	
t <sub>r</sub>	Turn-On Rise Time			4.5		ns	
t <sub>D(off)</sub>	Turn-Off DelayTime			15.5		ns	
t <sub>f</sub>	Turn-Off Fall Time			4.5		ns	
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6A, dI/dt=500A/μs		9		ns	
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-6A, dI/dt=500A/μs		13.5		nC	

A. The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150° C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25° C.

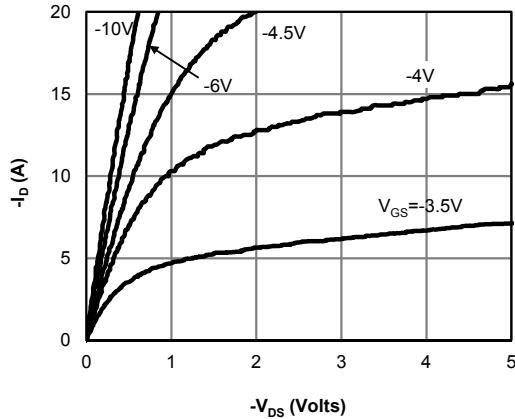
D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

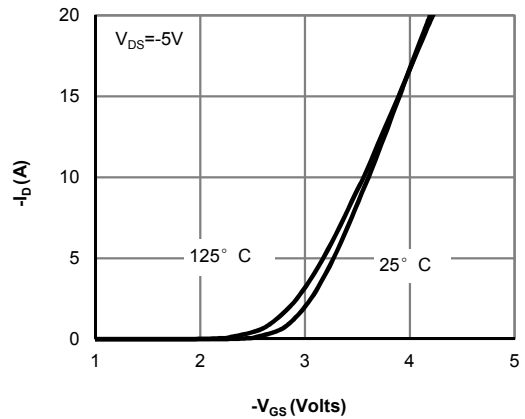
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.

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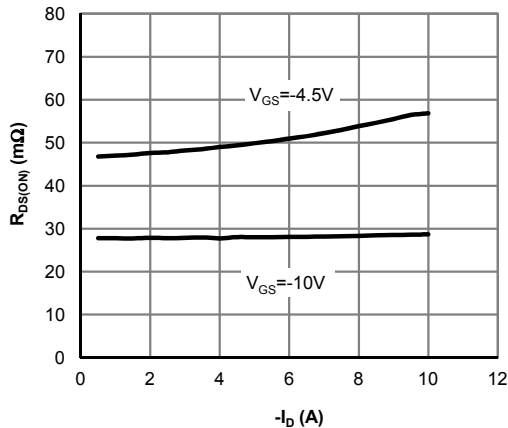
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



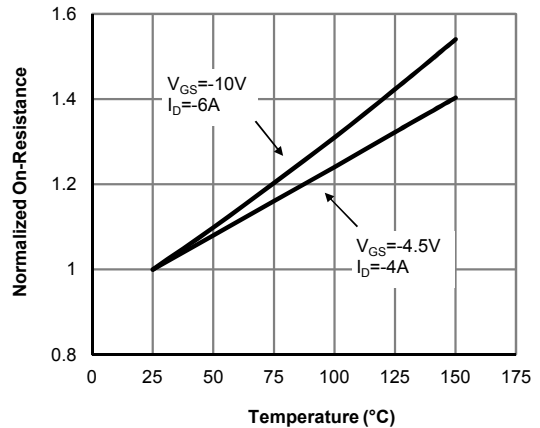
**Figure 1: On-Region Characteristics (Note E)**



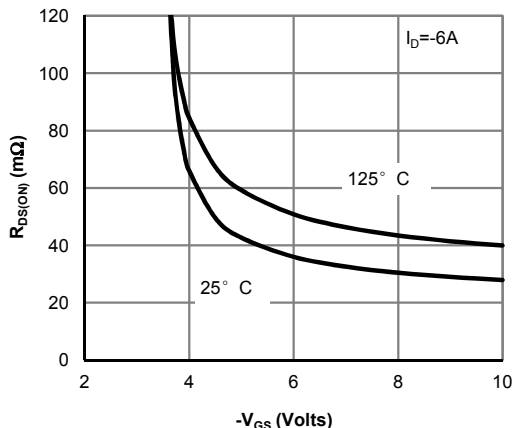
**Figure 2: Transfer Characteristics (Note E)**



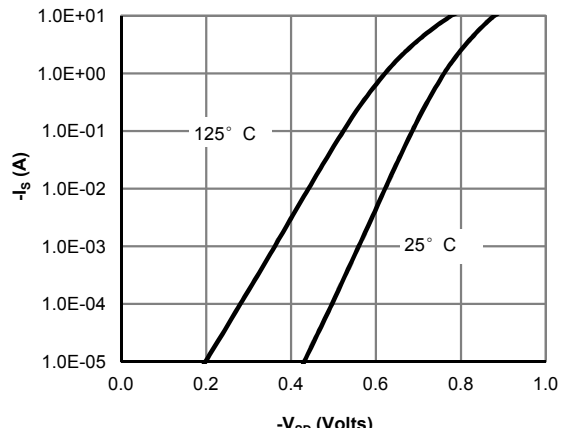
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**



**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

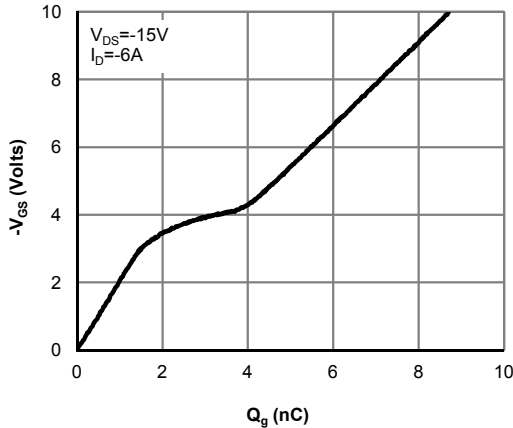


**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

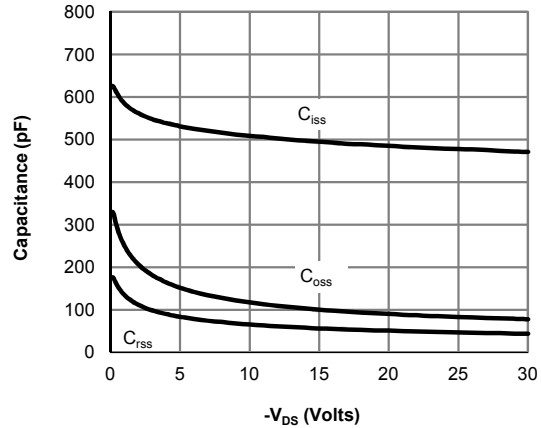


**Figure 6: Body-Diode Characteristics (Note E)**

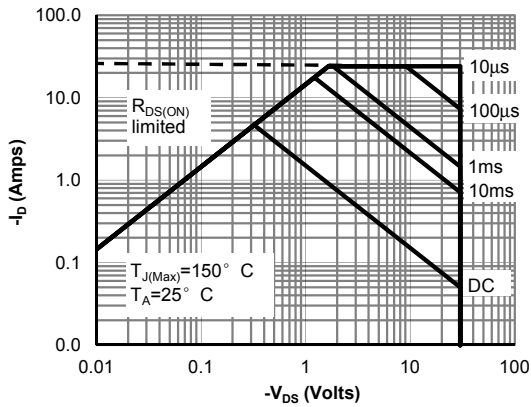
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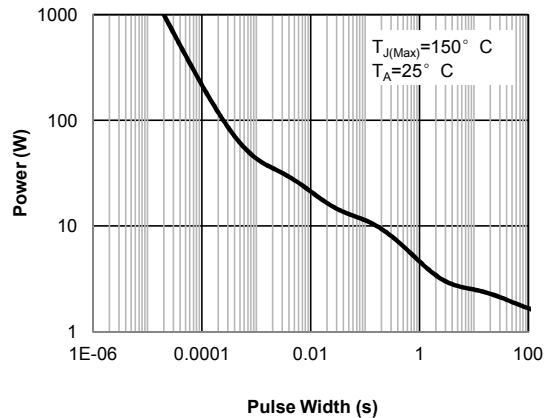
**Figure 7: Gate-Charge Characteristics**



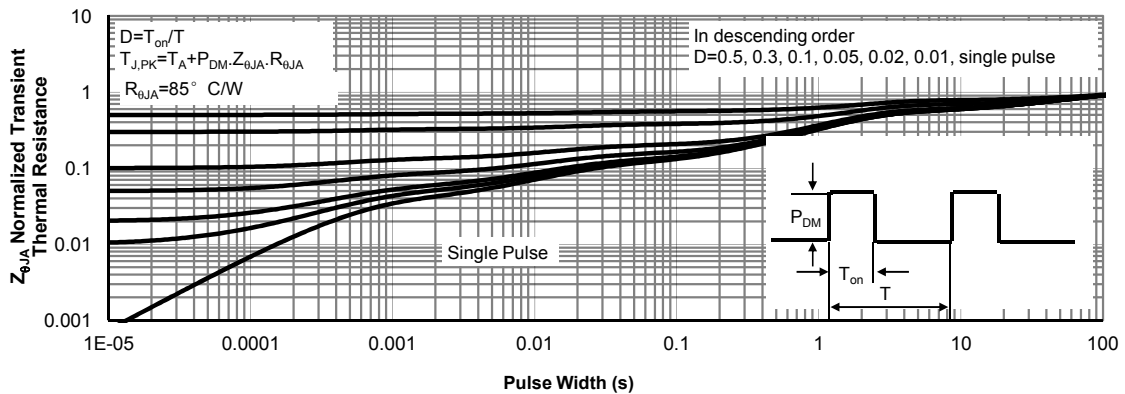
**Figure 8: Capacitance Characteristics**



**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

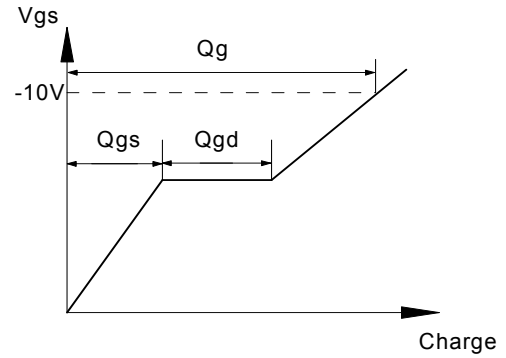
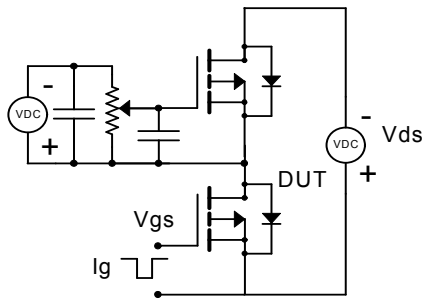


**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

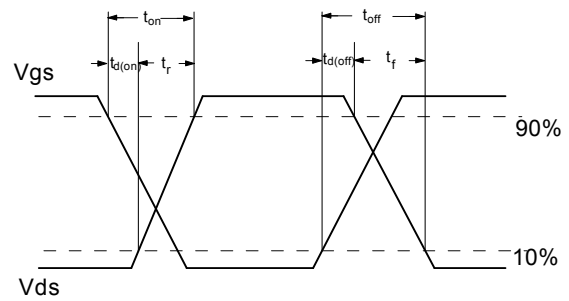
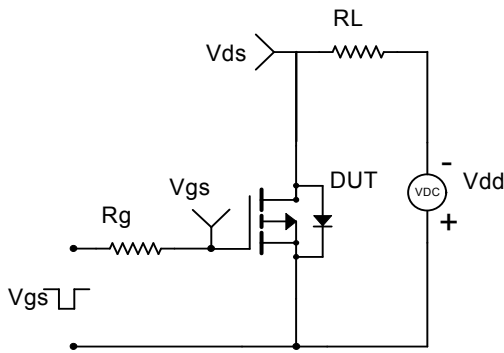


**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

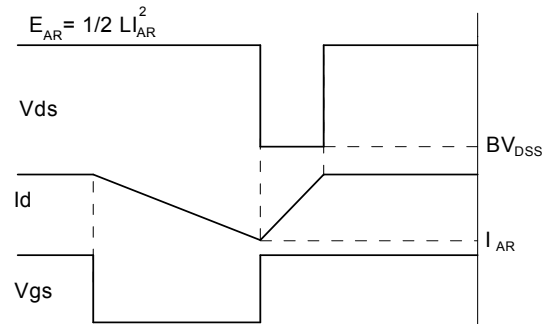
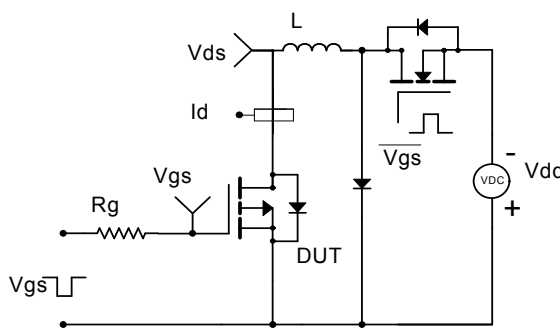
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



### Diode Recovery Test Circuit & Waveforms

